

Plasma Chemistry & Plasma Loading in an HPRF Cavity

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Processes

- There are four main processes associated with the HPRF cavity:
 - Plasma formation
 - &
 - Electron – ion interactions
 - Electron – neutral interactions
 - Ion – ion interactions

Plasma Formation

- The number of electron – ion pairs produced by a beam can be calculated

$$N_{pairs} = \frac{dE/dx \rho L}{W_i} N_{beam}$$

dE/dx = stopping power
 ρ = gas mass density
 L = beam path length
 W_i = avg. molecular ionization energy

Parameter	Units	MTA Beam (protons)	HCC Beam (muons)
Momentum (KE)	MeV / c (MeV)	956 (400)	200 (121)
Gas	-	H ₂ + Dry Air	H ₂ + O ₂
Dopant concentration	%	5	1
dE/dx	MeV cm ² / g	6.332	4.148
ρ	g / cm ³	0.00867	0.015
W_i	MeV	36.2	36.2
Bunch population	# / bunch	2×10^8	1×10^{12}
N_{pairs} / L	# / cm / bunch	3.50×10^{11}	1.88×10^{15}

Plasma Formation – II

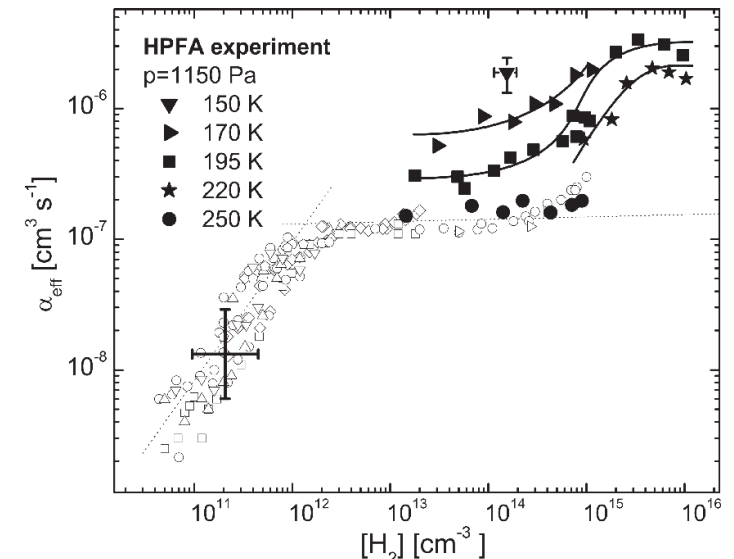
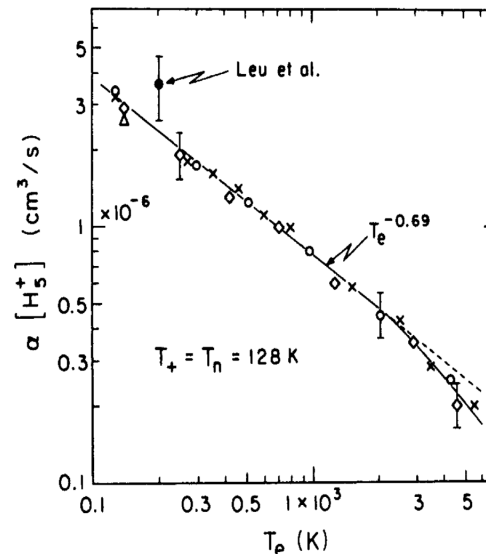
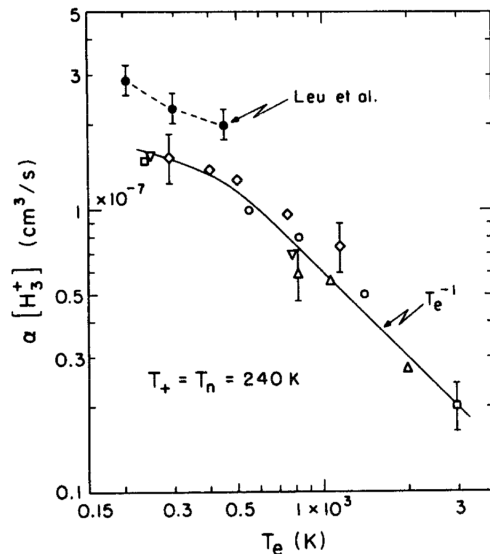
- Through collisions with gas molecules, electrons come into equilibrium (above room temperature) and drift with the RF field
 - Collision frequency: $64 \times 10^{12} \text{ s}^{-1}$ at 180 atm (30 ps equilibrium time)
 - Plasma frequency: $6.9 \times 10^{12} \text{ s}^{-1}$ (for $1.5 \times 10^{16} \text{ e}^-/\text{cm}^3$)
- The ions remain in thermal equilibrium with the surrounding gas
- The amount of energy dissipated, or “plasma loading” can be evaluated:

$$dw = q \int v E_0 \sin(\omega t) dt = q \int \mu E_0^2 \sin^2(\omega t) dt$$

$$v = \text{drift velocity} \quad \mu = \text{mobility}$$

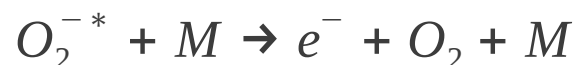
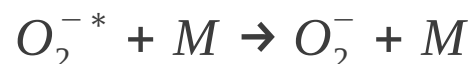
Electron – Ion Interactions

- Electrons may recombine with the hydrogen ions formed (H^+ , H_2^+ , H_3^+ , H_5^+ , H_7^+ ...)
- We had no way of distinguishing the ion cluster, and so measured an effective rate
- Our measurements are on the order of $10^{-7} - 10^{-6} \text{ cm}^3/\text{s}$, consistent with Literature measurements of H_3^+ and H_5^+
- ***Recombination rates tend to increase with gas pressure***

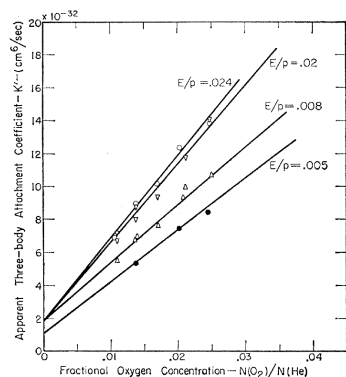


Electron – Neutral Interactions

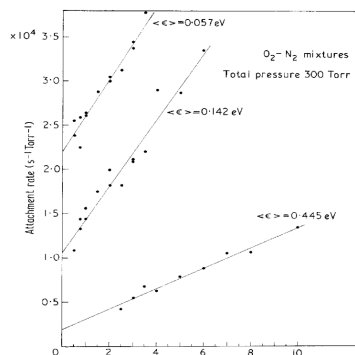
- Electrons can become attached to O_2 in three-body reactions, that at high densities look like two-body reactions



- The identity of the third body is important in the attachment process, and has been measured in great detail for N_2 and O_2 , but not for H_2



Chanin et al, Phys. Rev., Vol. 128, No. 1, 1962



McCorkle et al, J. Phys. B: Atom. Molec. Phys., Vol. 5, June 1972

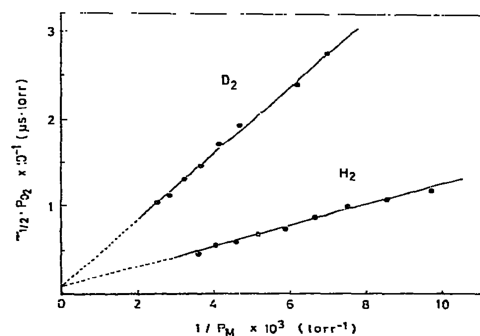


Fig. 4. $\tau_{1/2} P_{O_2}$ versus $1/P_{H_2}$, $1/P_{D_2}$ ($P_{O_2}/P_{H_2} = 0.0188$, $P_{O_2}/P_{D_2} = 0.00217$).

Shimamori and Hatano, Chem. Phys. Lett., Vol. 38, No. 2, 1976

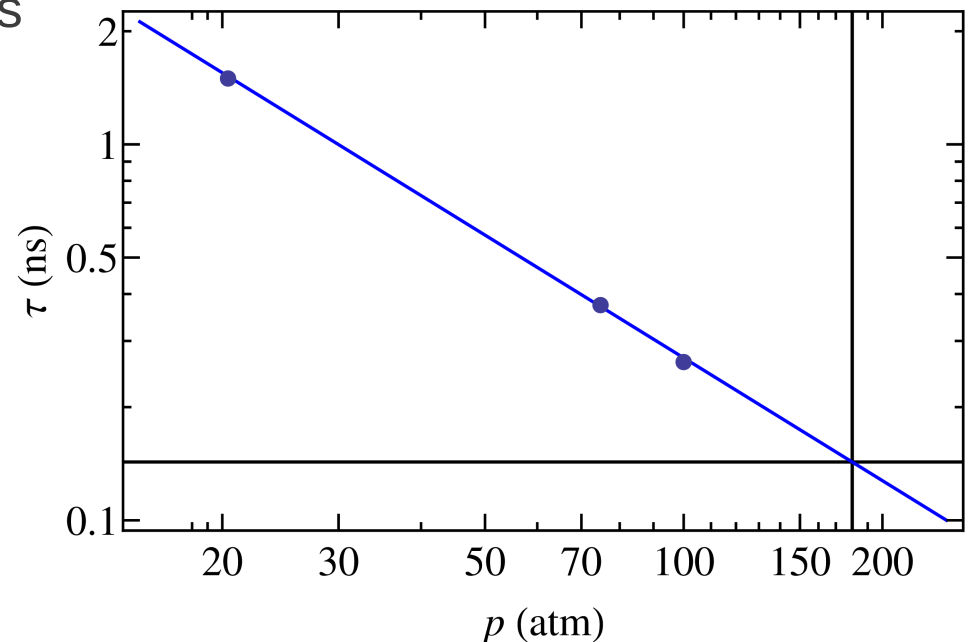
B	$k_a, 10^{-30} \text{ cm}^6/\text{s}$	$p, \text{ torr}$
A = O_2		
O_2	2.4 ± 0.1	30–300
	2.2 ± 0.2	100–400
	2.6 ± 0.1	250–600
	2.8	7–55
	2.0 ± 0.2	10–500
	3	3–30
	2.12 ± 0.14	1–10
	2.2 ± 0.1	2–100
	1.7	10–100
	2.1 ± 0.2	1–150
	2.2	5–25
	0.033 ± 0.003	160–425
He	0.028	7–55
	0.076	1–150
Ne	0.023 ± 0.003	90–300
Ar	0.05 ± 0.01	100–300
Kr	0.05 ± 0.01	60–200
Xe	0.085 ± 0.005	35–170
N_2	0.085 ± 0.003	30–300
	0.5	15–150
	0.26	10–100
	0.11	1–150
	0.11	5–20
H_2	0.48 ± 0.03	100–300
D_2	0.140 ± 0.005	140–400
H_2O	14 ± 5	250–600

Electron – Neutral Interactions II

- Our third bodies are mostly H_2 , with some N_2 and O_2
- The rate equation for electrons is:

$$\frac{dn_e}{dt} = \dot{N} - \beta n_e n_{H^+} - \frac{n_e}{\tau} \quad \beta n_e n_{H^+} = \sum_l \beta_l n_e n_{H_l^+} \quad \frac{n_e}{\tau} = \sum_M k_M n_e n_{O_2} n_M$$

- Using our measurements of the recombination rate in pure hydrogen and energy loss per electron-ion pair, the measured power loss can be fit to give the attachment time of electrons
- On the right are the extrapolated attachment times for H_2 doped with 1% dry air at an $E/P = 20$ MV/m / 180 atm
- The prediction at 180 atm is 142 ps



Ion – Ion Interactions

- Because the electrons go away so fast, ions play a significant role in plasma loading
- No work has been done on hydrogen-oxygen ion recombination, however other ions have been studied
 - Rates fall with E/P
 - Above 1 atm, rates fall with P
- Our data shows similar trends – the ion-ion recombination rate predicted is on the order of 10^{-9} cm³/s at 180 atm and 20 MV/m
- This is not fast enough to negate the ions within a beam pulse
- Luckily ions load the cavity ~100 times less than electrons

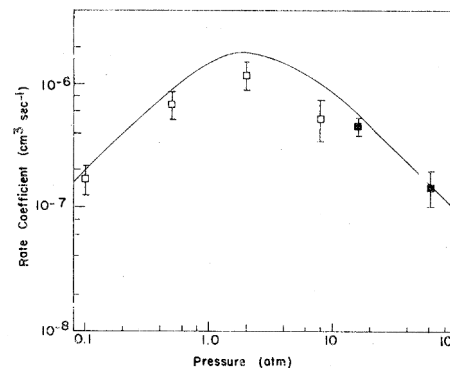


FIG. 4. $\text{Kr}^+ + \text{F}^-$ Ar recombination-rate coefficient. Solid line is curve (2) from Fig. 1. Points \square are MD calculations for $n_i = 10^{13} \text{ cm}^{-3}$ using MD option (iii) (see Sec. IV of text). Points \blacksquare are MD calculations for $n_i = 10^{15} \text{ cm}^{-3}$ using MD option (iv).

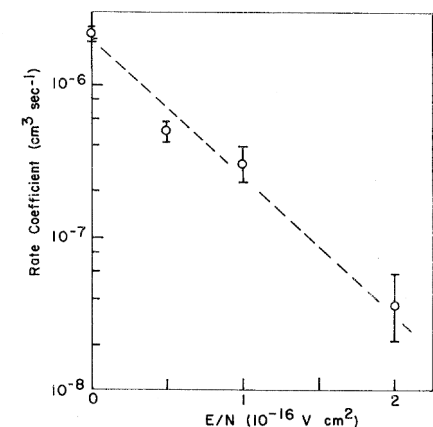
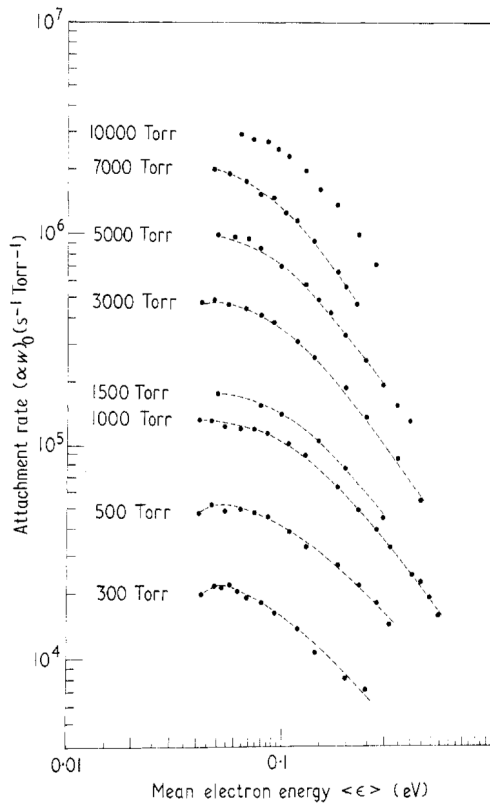


FIG. 6. $\text{Kr}^+ + \text{F}^-$ He recombination-rate coefficient vs discharge E/N for $P = 3 \text{ atm}$ and $n_i = 10^{15} \text{ cm}^{-3}$.

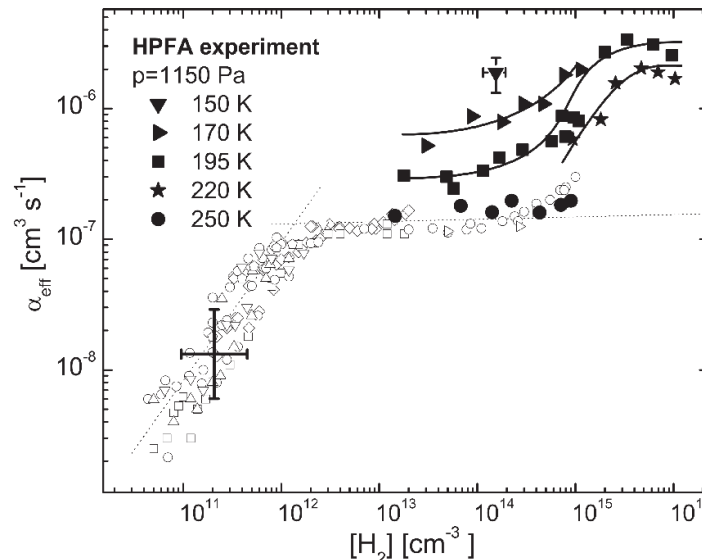
Pressure Effects

- It is known that gas and plasma density affects the mobility (drift velocity), recombination rate, and attachment rates



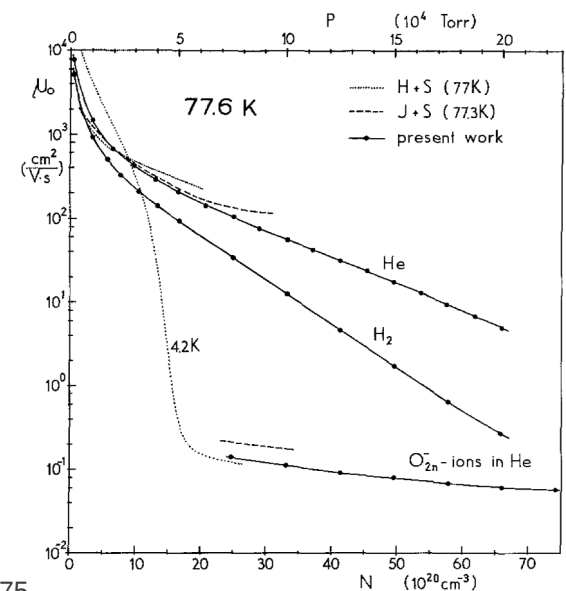
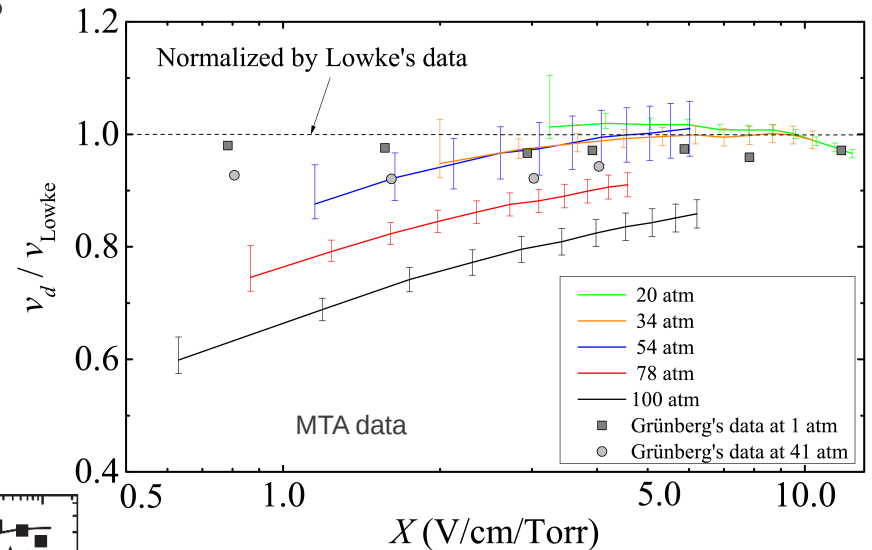
McCorkle et al, J. Phys. B: Atom. Molec. Phys., Vol. 5, June 1972

All effects are in the positive direction



Glosik et al, Plasma Sources Sci. Technol. 12 (2003)

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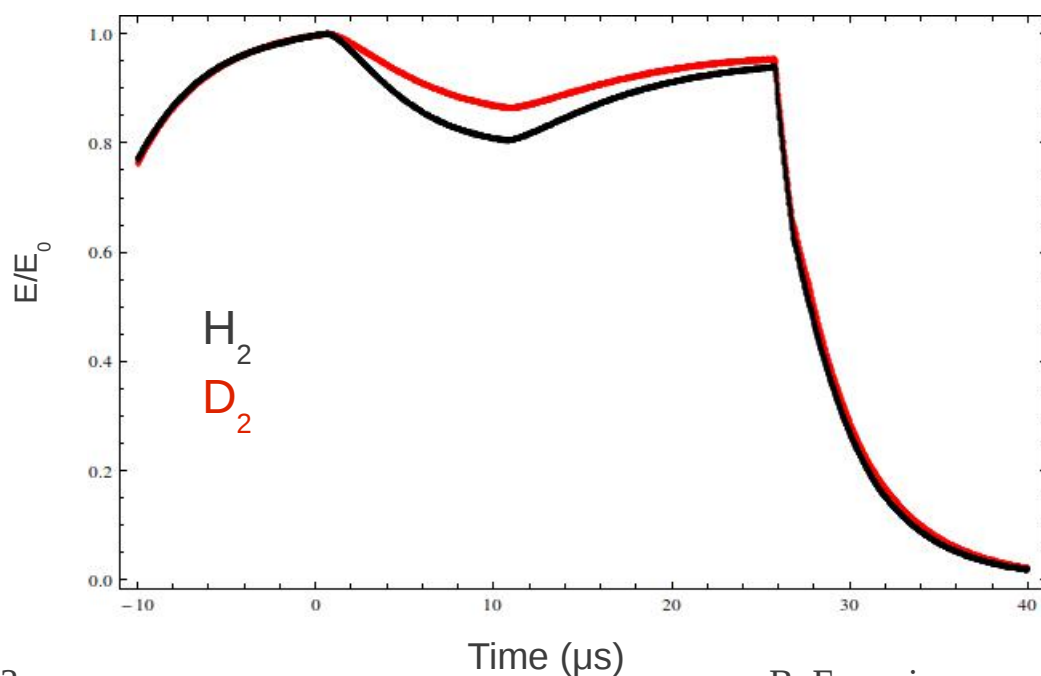
Bartels, Appl. Phys.8, 59-64, 1975

Gases Studied

- Energy loss and electron-ion recombination rates have been measured for the following gases:
 - H_2 , D_2 , He, N_2
- Electron attachment time and ion-ion recombination rates have been measured for the following gas combinations:
 - $\text{H}_2 + \text{DA}$, $\text{H}_2 + \text{N}_2$, $\text{H}_2 + \text{SF}_6$, $\text{D}_2 + \text{DA}$, He+DA, $\text{N}_2 + \text{DA}$
- Due to its high boiling point, SF_6 would have to be used at room temperature
- The only suitable electronegative dopant appears to be O_2 – a small amount ($\sim 1\%$) does not significantly change the radiation length of the gas
- H_2 or D_2 appear to be the only candidates with suitable stopping power in the 200 MeV/c μ momentum range

Hydrogen vs Deuterium

- D_2 ions load the cavity less than H_2 ions due to their larger mass
- Initial results also indicate the ion-ion recombination rates for D_2 are larger than those for H_2
- Data was taken with only one gas pressure and one dopant concentration
 - More data is needed to reach any conclusions

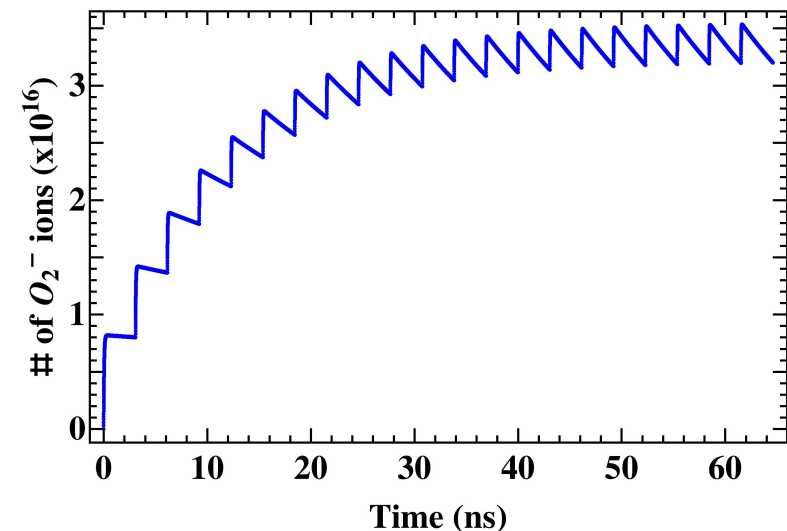
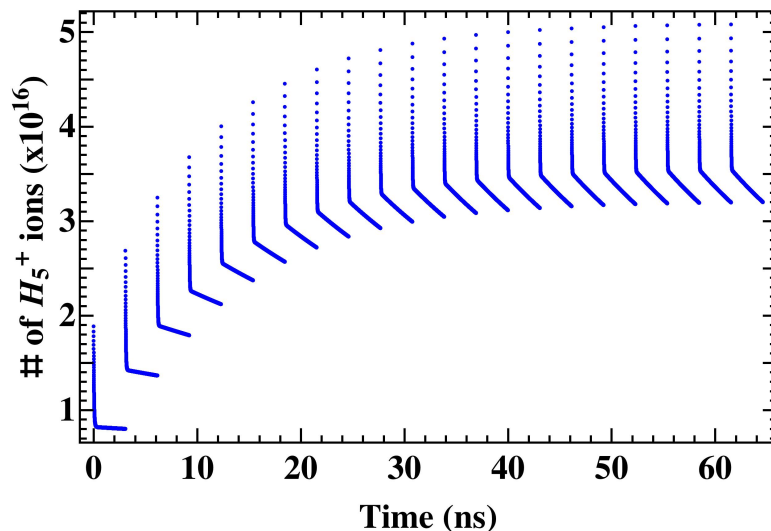
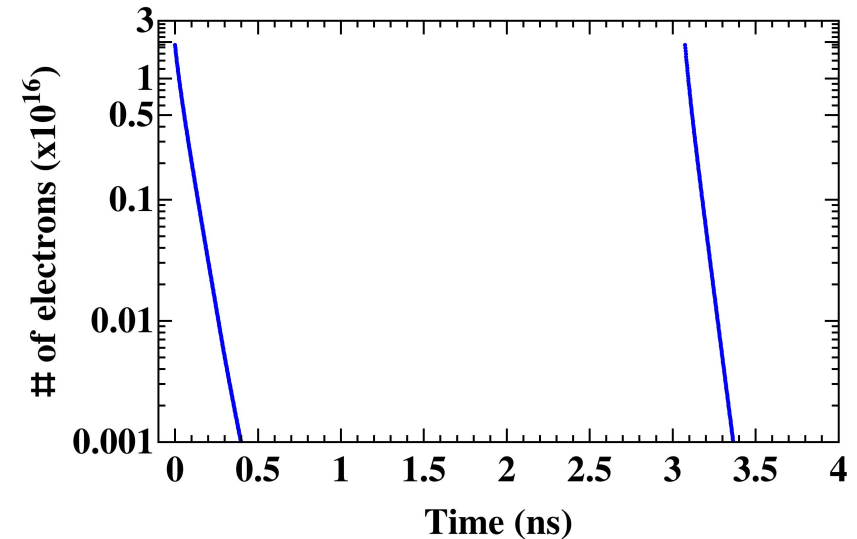


Plasma Loading Calculation

- Input parameters (derived from beam test data):
 - Electron attachment time
 - Electron – hydrogen recombination rate
 - Hydrogen – oxygen recombination rate
 - Electron drift velocity (constant)
 - Ion energy loss
- Assumptions:
 - 325 MHz bunched beam
 - 21 delta function bunches
 - 160° injection (relative to RF)
 - 20 MV/m peak E field
 - 180 atm H₂ gas with 1% DA
 - 10 cm long cavity
 - Recombination rates constant (10^{-6} cm³/s e-H, 10^{-9} cm³/s O-H)
 - 1 cm³ plasma volume (homogeneous density)
 - Attachment time varies with E field (100 ps min.)
 - Cavity voltage not affected by plasma loading

Plasma Loading Calculation Results

- The total number of each charged particle species is tracked over 21 beam pulses
- Electrons “decay” very quickly, however ions build up over time
- Time step is 1/1000 of an RF period
- 650 MHz RF, 10^{12} μ /bunch is shown



Plasma Loading Calculation Results – II

- Two RF frequencies and two bunch intensities were considered
- In all cases, plasma loading was minimal

Parameter	Unit	Value			
RF frequency	MHz	325		650	
Stored energy	J	19		4.7	
μ /bunch	#	10^{11}	10^{12}	10^{11}	10^{12}
Electron dissipated energy	J	0.014	0.072	0.012	0.062
Ion dissipated energy	J	0.010	0.029	0.020	0.059
Total dissipated energy	J	0.024	0.101	0.032	0.121
% of V_{accel} seen by last bunch	%	99.9	99.7	99.7	98.7

Conclusions

- Based on extrapolation of parameters measured during the MTA HPRF beam test, plasma loading appears to be minimal in a HCC
- The effects of higher gas and plasma densities must be investigated
 - All signs point to positive effects
 - Experimental data will be difficult to obtain
 - Simulation must be relied upon in the meantime